

Notice of References Cited	Application/Control No. 10/521,718	Applicant(s)/Patent Under Reexamination NEERVOORT ET AL.	
	Examiner Thu V. Huynh	Art Unit 2178	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0227438	12-2003	Campbell et al.	345/156
*	B	US-2001/0040532	11-2001	YASUDA, HITOSHI	345/1.1
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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